

# AscenPower Semiconductors 芯粤能半导体



# AscenPower Semiconductor

The 1<sup>st</sup> SiC Power Device Foundry authorized by China Central Government



**Automotive-grade SiC Power Device R&D and Fabrication**

| **Foundation** 2021.5.17

| **Mission** AscenPower! Empower!

| **Vision** To be the trusted partner in SiC power device world!

Investment(RMB)

7.5  
billion

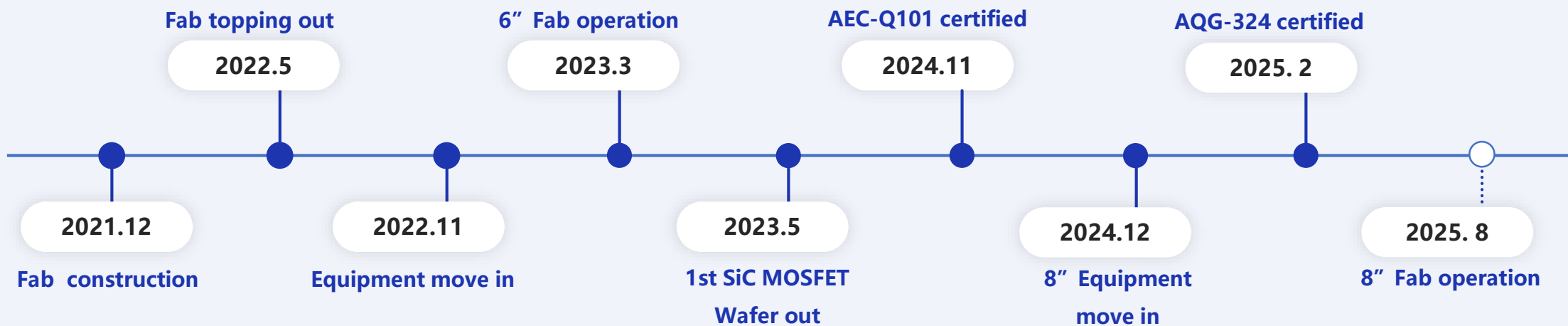
Capacity (kwfs/year)

240 (6")  
+  
240 (8")

Management

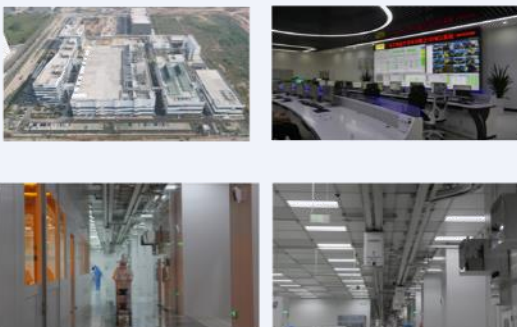
Top  
500

# AscenPower Milestones



## Clean Room

全自动化碳化硅工厂



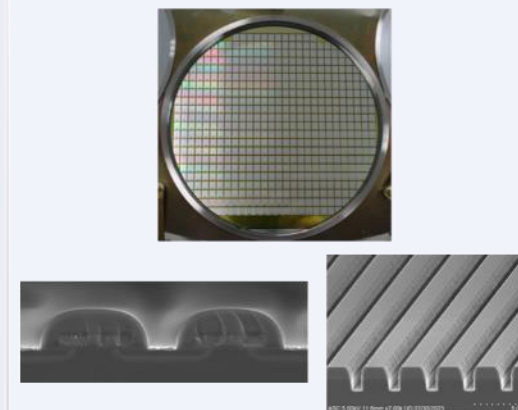
## Equipment

一流的碳化硅器件生产设备



## Technology

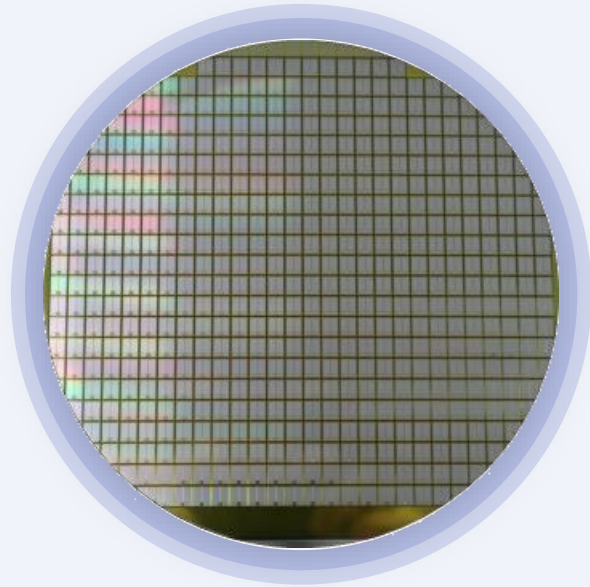
完善的碳化硅工艺平台



# Strategic Partnerships



SiC substrate & epitaxy  
**Strategic Partners**



Automotive-grade  
SiC power device manufacturing  
**AscenPower**



Automotive-grade  
SiC package & modules  
**AccoPower**



Traction inverter  
**VREMT**



EVs  
**ZEEKR**

Shareholder: 34.9%

Automotive-grade SiC Power Modules Manufacturer  
Top-10 SiC power modules suppliers in China

Shareholder: 26.1%

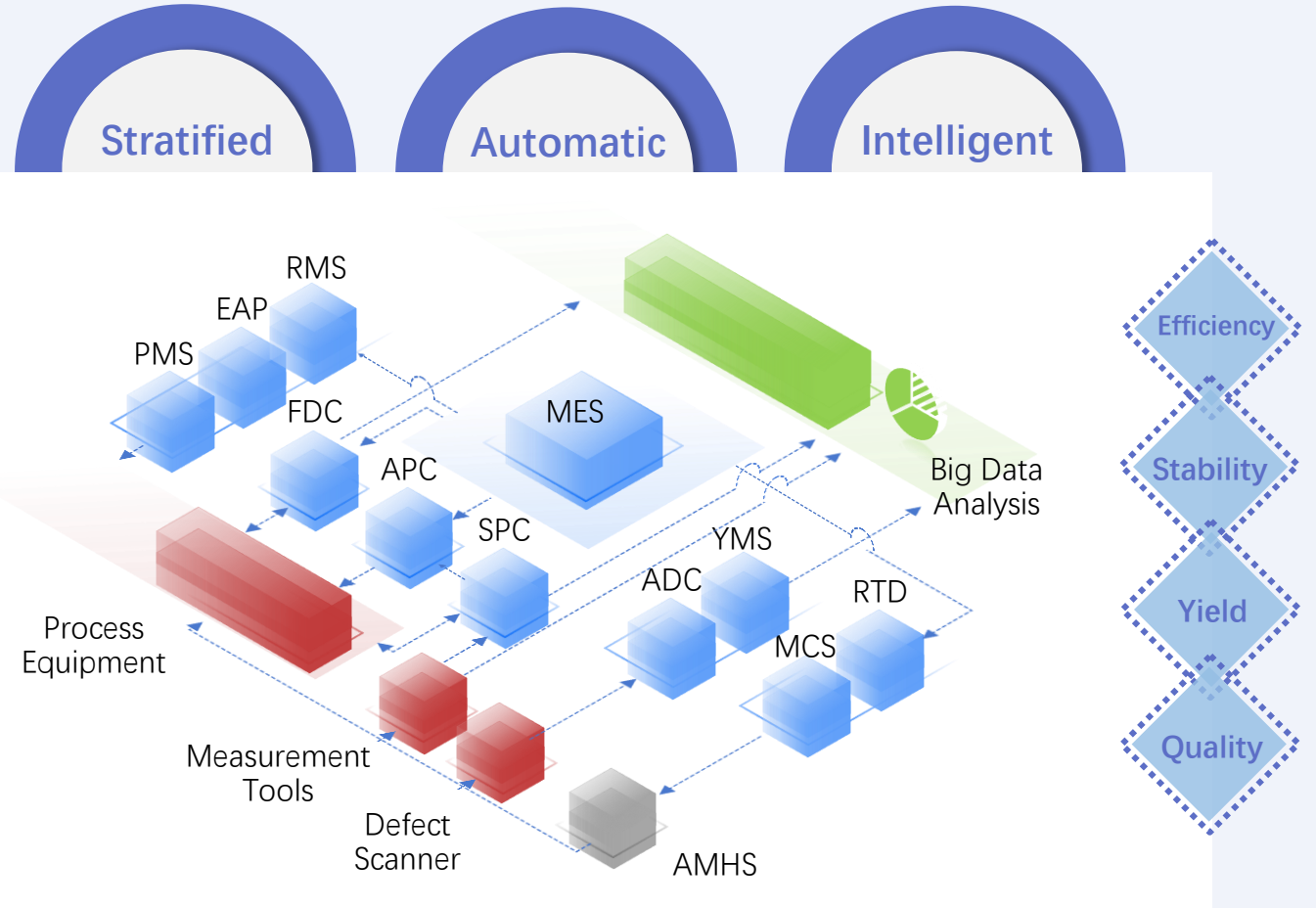
Tier-1 of ZEEKR under Geely holding group

# Fully Automated SiC Fab for Mass Production



AMHS

AscenPower is the 1<sup>st</sup> SiC foundry in China that introduced AMHS system



# SiC FAB(6") Quality System Certification



**bsi.**    
By Royal Charter

## Certificate of Registration

质量管理体系 - IATF 16949:2016

兹证明: 广东芯粤能半导体有限公司  
91440101MA9XTDPE0G  
中国  
广东省  
广州市  
南沙区  
正翔路10号  
邮编: 511464

AscenPower Semiconductors Co., Ltd.  
No. 10, Zhengxiang Road  
Nansha District  
Guangzhou  
Guangdong  
511464  
China

USI: L6NESS

并运行符合 IATF 16949:2016 要求的质量管理体系, 认证范围如下:

半导体芯片的生产。  
允许删减: 产品设计。  
The manufacture of semiconductor wafers.  
Permitted Exclusions: Product design.

BSI代表:   
Michael Lam - Managing Director Assurance, APAC

BSI证书号码: 812976  
IATF Number: 0541409



认证日期: 2024-08-28

Page: 1 of 1

最新发证日期: 2024-08-28 有效期至: 2027-08-27

...making excellence a habit.™

**bsi.**    
By Royal Charter

## Certificate of Registration

质量管理体系 - ISO 9001:2015

兹证明: 广东芯粤能半导体有限公司  
91440101MA9XTDPE0G  
中国  
广东省  
广州市  
南沙区  
正翔路10号  
邮编: 511464

AscenPower Semiconductors Co., Ltd.  
No. 10, Zhengxiang Road  
Nansha District  
Guangzhou  
Guangdong  
511464  
China

持有证书: **FM 813059**

并运行符合 ISO 9001:2015 要求的质量管理体系, 认证范围如下:

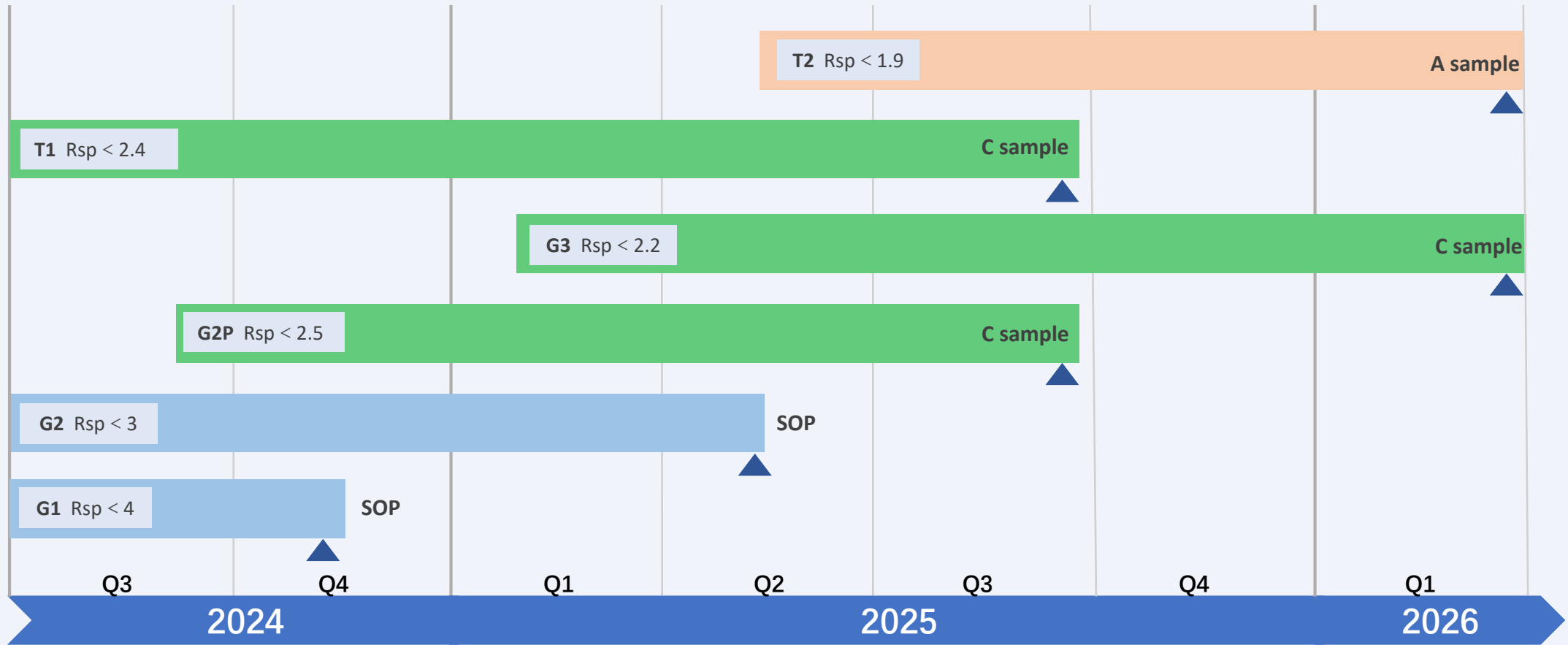
半导体芯片的生产。  
The manufacture of semiconductor wafers.

BSI代表:   
Michael Lam - Managing Director Assurance, APAC

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# SiC MOSFET Technology Road Map



G1/2/2P/3 Planar

T1/T2 Trench

Production

Developing

Researching

# AEC-Q101: G1\_1200V/16mohm SiC MOSFET



**GRGTEST**  
第 1 页 共 406 页

## AEC-Q101 可靠性试验报告

校验码: 547776

报告编号: R202407087688-01

委托单位: 广东芯粤能半导体有限公司  
单位地址: 中国广东省广州市南沙区正翔路 10 号  
样品名称: AM16H120B1N (M000101C)  
型号规格: TO247 1200V 16mOhm  
样品信息: 详见第 2 部分  
收样日期: 2024/07/06  
试验依据: AEC-Q101-Rev-E March 1, 2021  
试验日期: 2024/07/06 ~ 2024/11/22  
试验结果: 详见正文

编制: 任家辉 审核: 邹国锋 批准: 李汝冠

广电计量检测集团股份有限公司  
工业和信息化部集成电路芯片应用验证平台  
地址: 广东省广州市番禺区创逸路 8 号  
电话 (Tel): (+86) 400-602-0999 传真 (FAX): (+86) 020-38608685 网页: <http://www.grgtest.com>

R202407087688-01

## • TO247-4

Test Description	Stress Condition	Duration	Results
<b>HTGB+</b> (High Temperature Gate Positive Bias)	Ta=175°C, Vgs=+22V Per JESD22-A108	1000hrs	PASS
<b>HTGB-</b> (High Temperature Gate Negative Bias)	Ta=175°C, Vgs=-20V Per JESD22-A108	1000hrs	PASS
<b>HTRB</b> (High Temperature Reverse Bias)	Ta=175°C, Vds=1200V Per JESD22-A108	2000hrs	PASS
<b>HV-H3TRB</b> (High Voltage High Temperature High Humidity Reverse Bias)	85°C, 85%RH, Vds=960V Per JESD22-A101	1000hrs	PASS
<b>TC</b> (Temperature Cycling)	-55°C-150°C Per JESD22-A104	1500cycls	PASS

## • HPD-Module

Test Description	Stress Condition	Duration	Results
<b>HTGB+</b> (High Temperature Gate Positive Bias)	Ta=175°C, Vgs=+22V Per JESD22-A108	1000hrs	PASS
<b>HTGB-</b> (High Temperature Gate Negative Bias)	Ta=175°C, Vgs=-10V Per JESD22-A108	1000hrs	PASS
<b>HTRB</b> (High Temperature Reverse Bias)	Ta=175°C, Vds=960V Per JESD22-A108	1000hrs	PASS
<b>HV-H3TRB</b> (High Voltage High Temperature High Humidity Reverse Bias)	85°C, 85%RH, Vds=960V Per JESD22-A101	1000hrs	PASS

# AQG-324: G1\_1200V/16mohm SiC MOSFET + V2P Module



文件编号: AP-PRE-95 REV6 报告编号: RE2024040

## 检测报告

单位地址: 广州市南沙区万顷沙正翔路 6 号

样品名称: ACCO PACK DRIVE B

样品型号: ACN03FT12V2PK

检测依据: AQG 324 03.1.2021

检测日期: 2024.11-2025.1

检测结论: 符合要求

报告编号: RE2024040

发布日期: 2025.03.15



文件编号: AP-PRE-95 REV6 报告编号: RE2024040

可靠性验证结果						
项目	描述	应力条件	应力时间	样本量	接收准则	结果
High Temp Storage (AQG324)	HTS	Tstg=125°C	1000h	6 module	0 Fail Accept, 1 Fail Reject.	PASS
Low Temp Storage (AQG324)	LTS	Tstg=-40°C	1000h	6 module	0 Fail Accept, 1 Fail Reject.	PASS
High Temp Reverse Bias (AQG324)	HTRB	Ta=175°C, VDS=1200V, VGS=0V	1000h	6 module	0 Fail Accept, 1 Fail Reject.	PASS
High Temp Gate Bias (AQG324)	HTGB	Ta=175°C, 3 module VGS=+22V,VDS=0V, 3 module VGS=-10V,VDS=0V	1000h	6 module	0 Fail Accept, 1 Fail Reject.	PASS
High Temperature and Humidity Reverse Bias (AQG324)	H3TRB	Ta=85°C, RH=85%, VDS=960V, VGS=0V	1000h	6 module	0 Fail Accept, 1 Fail Reject.	PASS



文件编号: AP-PRE-95 REV6 报告编号: RE2024040

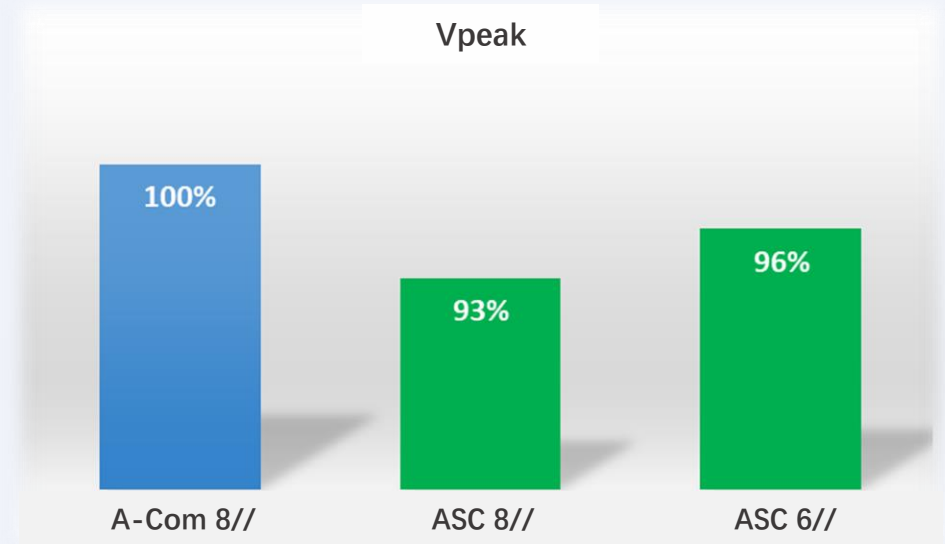
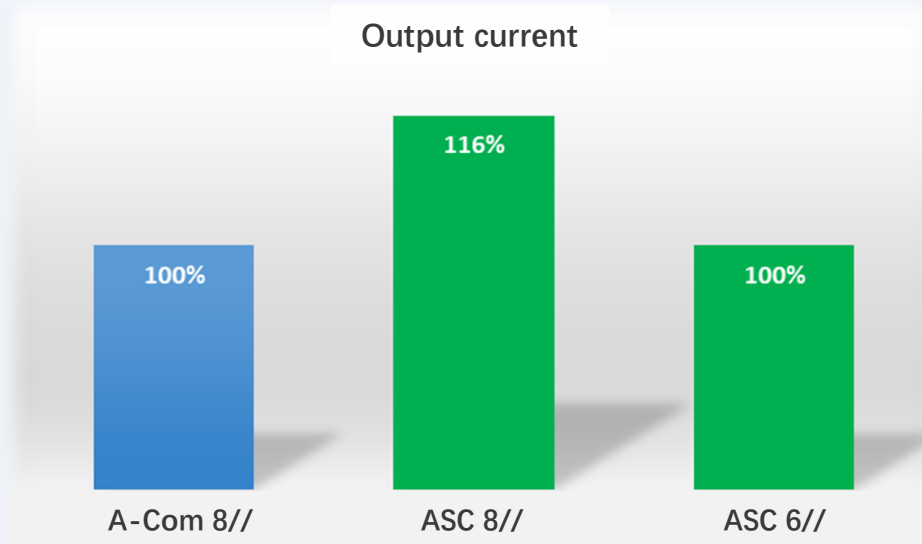
可靠性验证结果														
项目	描述	应力条件	应力时间	样本量	接收准则	结果								
Thermal Shock Test (AQG324)	TST	-40°C to +125°C, Tchange < 30s, TDUT dwell > 15min	1000cyc	6 module	0 Fail Accept, 1 Fail Reject.	PASS								
Vibration (AQG324)	V	X/Y/Z 3 direction, 22h per direction, 1 octave/min, 对数扫描: <table border="1"> <tr> <th>频率(Hz)</th> <th>加速度振幅(m/s²)</th> </tr> <tr> <td>100</td> <td>30</td> </tr> <tr> <td>200</td> <td>60</td> </tr> <tr> <td>440</td> <td>60</td> </tr> </table>	频率(Hz)	加速度振幅(m/s²)	100	30	200	60	440	60	22h each direction	6 module	0 Fail Accept, 1 Fail Reject.	PASS
		频率(Hz)	加速度振幅(m/s²)											
		100	30											
		200	60											
440	60													
X/Y/Z 3 direction, 22h per direction: <table border="1"> <tr> <th>振动方式</th> <th>宽频随机振动</th> </tr> <tr> <td>每方向上持续时间</td> <td>22h</td> </tr> <tr> <td>加速度均方根</td> <td>96.6m/s²</td> </tr> </table>	振动方式	宽频随机振动	每方向上持续时间	22h	加速度均方根	96.6m/s²								
振动方式	宽频随机振动													
每方向上持续时间	22h													
加速度均方根	96.6m/s²													
振动曲线	功率谱密度 (m/s²)/Hz													
	10	10												
	100	10												
	300	0.51												
500	5													
2000	5													

Mechanical Shock (AQG324)	MS	10 times shock in x, y, z 6 direction each, Shock form: half-sine, Peak acceleration: 500m/s², Shock duration: 6ms.	10 times shock in each direction	6 module	0 Fail Accept, 1 Fail Reject.	PASS
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Power Cycling(sec) (AQG324)	PCsec	PCsec Iload=const, ton=const and<5s, Iload≥0.85I <sub>o</sub> , Tvjmax=175°C, ΔTvj=100K	Nfs50000cyc	6 module	0 Fail Accept, 1 Fail Reject.	PASS
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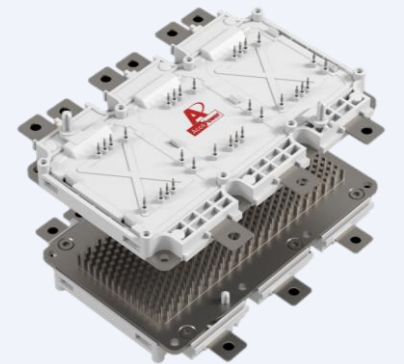
Power Cycling(min) (AQG324)	PCmin	PCmin Iload=const, ton=const and>15s, Iload≥0.85I <sub>o</sub> , Tvjmax=175°C, ΔTvj=100K	Nfs20000cyc	6 module	0 Fail Accept, 1 Fail Reject.	PASS
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# G1\_1200V/16mohm SiC MOSFET + AccoPower V2P Module

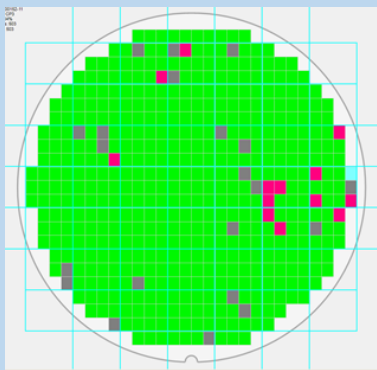


## ASC vs A-com:

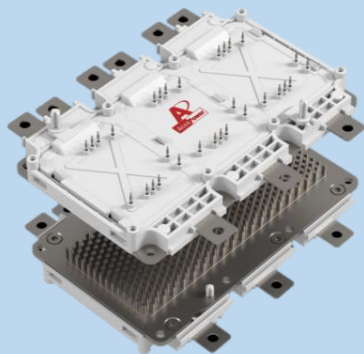
- ✓ Same chip quantity in parallel(8//), Higher output current(I<sub>d</sub>) level +16%
- ✓ Same output current level, Less SiC MOSFET chips in V2P module -25%
- ✓ In term of peak V<sub>ds</sub>, voltage stress is lower.



# 1<sup>st</sup> Main Inverter with G1 SiC MOSFET



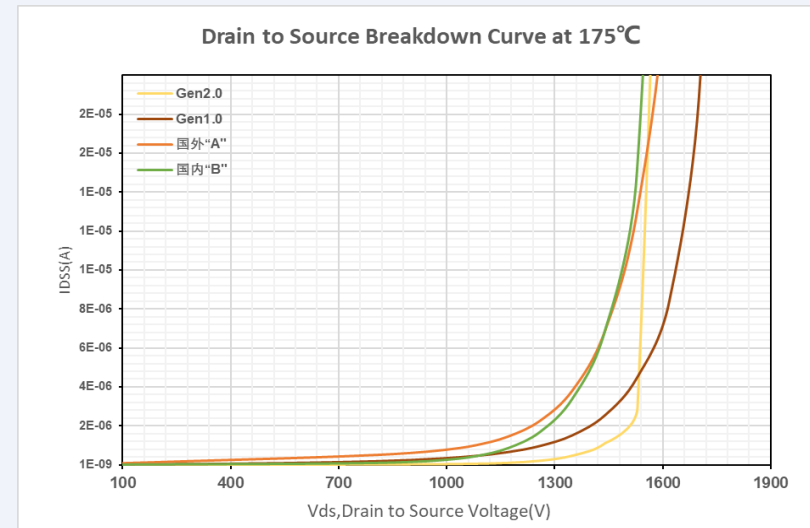
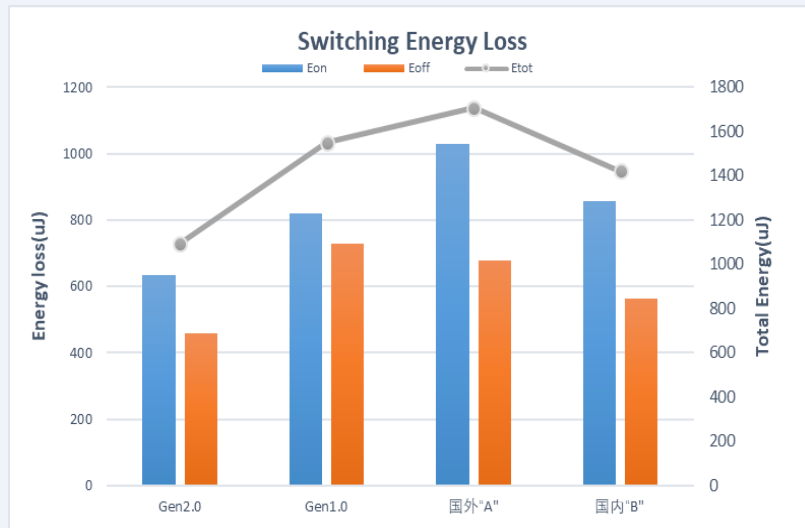
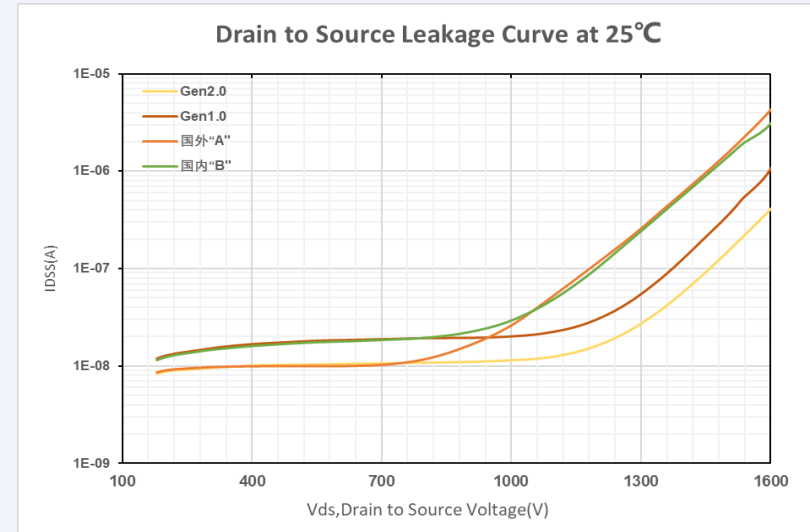
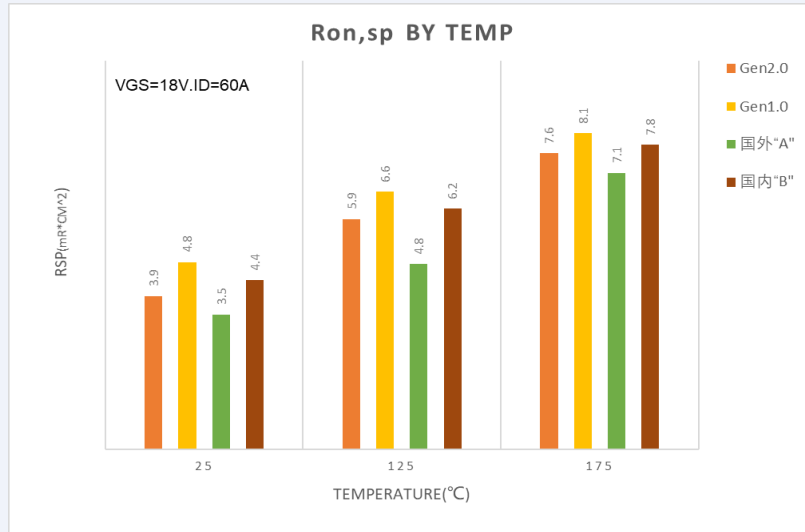
AscenPower SiC MOSFET



AccoPower V2P Module



# G2 SiC MOSFET Performance



# G2: 1200V/30mohm SiC MOSFET Reliability

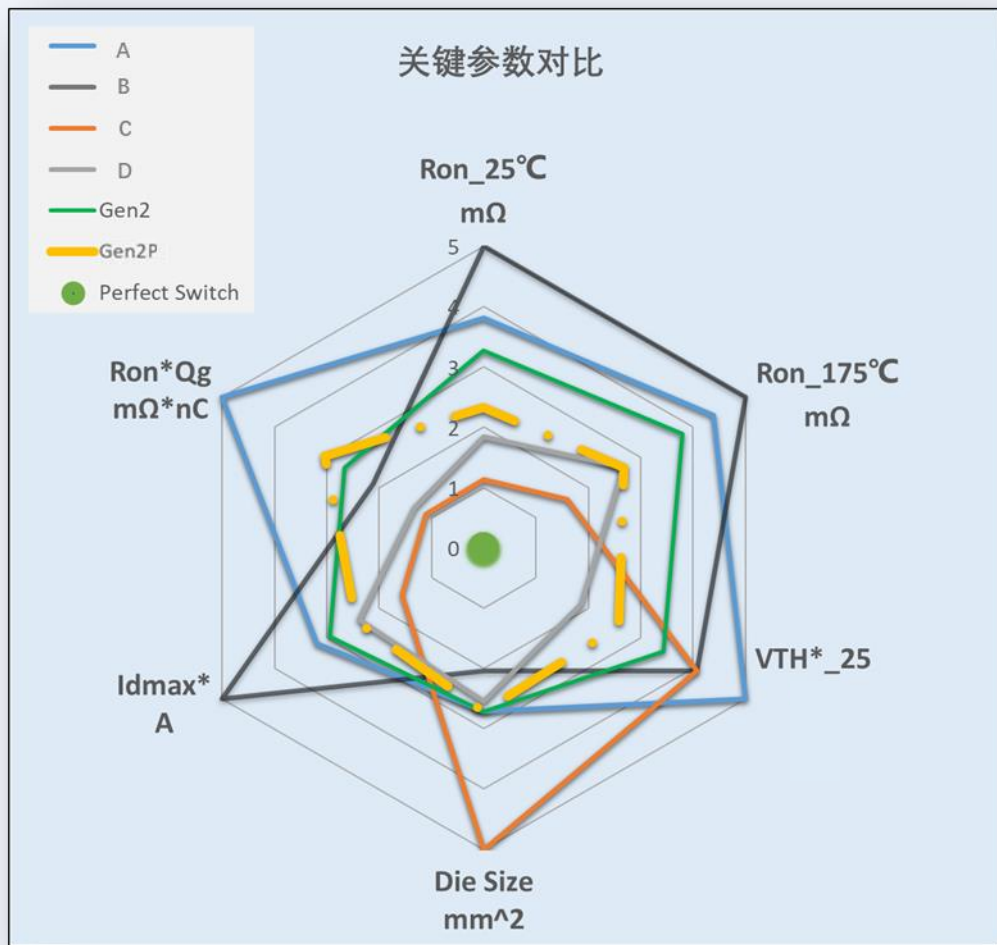


3 lots samples passed all AEC-Q101 items + HV H3TRB

Test item	Test plan	Lot1	Lot2	Lot3
HV H3TRB	Ta = 85°C, 85% RH, Vds=960V Vgs=0V, 1000hrs	Pass (0/77)	Pass (0/77)	Pass (0/77)
UHASt	130°C, 85% RH ,18.8 psig, 96hrs	Pass (0/77)	Pass (0/77)	Pass (0/77)
TC	-55°C to 150°C, 1000cycles	Pass (0/77)	Pass (0/77)	Pass (0/77)
IOL	Delta Tj 100C, Ton&Toff 3min,1000hrs	Pass (0/77)	Pass (0/77)	Pass (0/77)
HTRB	Ta= 175°C , Vgs=0,Vds = 1200V,1000hrs	Pass (0/77)	Pass (0/77)	Pass (0/77)
HTPGB	Ta= 175°C , Bias = Positive max Vgs 22V,1000hrs	Pass (0/77)	Pass (0/77)	Pass (0/77)
HTNGB	Ta= 175°C , Bias = Negative max Vgs -10V,1000hrs	Pass (0/77)	Pass (0/77)	Pass (0/77)



# G2P 1200V 13mohm SiC MOSFET



Device	$R_{on\_25^{\circ}C}$ m $\Omega$	$R_{on\_175^{\circ}C}$ m $\Omega$	$V_{TH\_25^{\circ}C}$ V	Die Size mm $^2$	$I_{dmax}$ A
A	14	25	2.5	25	149
B	16.0	26.4	2.7	25	125
C	9.5	18.5	2.7	30	180
D	10.7	21	3.3	25	163
Gen2	15.1	27.6	2.9	25	153
Gen2P	12.5	22.0	3.1	25	162

## 1200V Gen2P highlights:

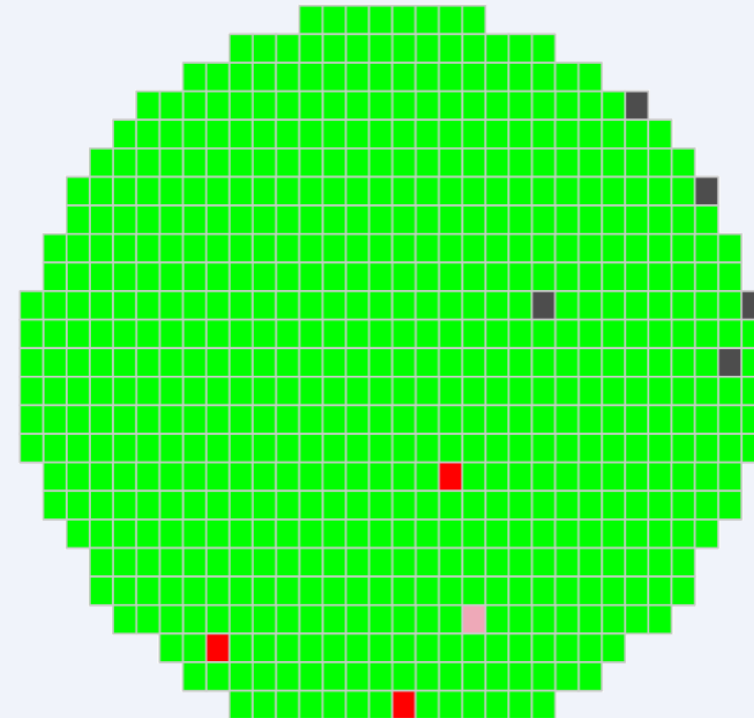
- More balanced performance
- Flexible customized  $R_{on}$ 
  - ~13mohm 25mm $^2$  chip size
  - ~10mohm 30mm $^2$  chip size
- Faster development for 750V grade

# T1 SiC MOSFET(trench) Platform (Launched @2025 Mar)



1200V T1 SiC MOSFET Ron,sp(mΩ·cm <sup>2</sup> )			
R-Com	I-Com	B-Com	ASC
2.25	2.38	2.31	2.30

		T1 1200V/13mohm	
Test Description	Stress Condition	Duration	Results
HTPGB	Ta=175°C, Vgs=+22V	1000hrs	PASS
HTNGB	Ta=175°C, Vgs=-10V	1500hrs	PASS
HTRB	Ta=175°C, Vds=1200V	1500hrs	PASS
HV-H3TRB	85°C, 85%RH, Vds=960V	1500hrs	PASS
TC	-55°C-150°C	1500cycs	PASS



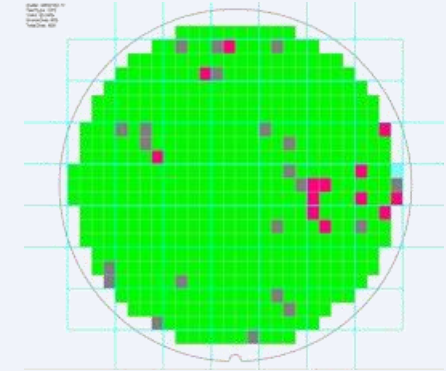
Wafer CP yield map: 98.58%

# Cooperative business scenarios



## ➤ Turn key service

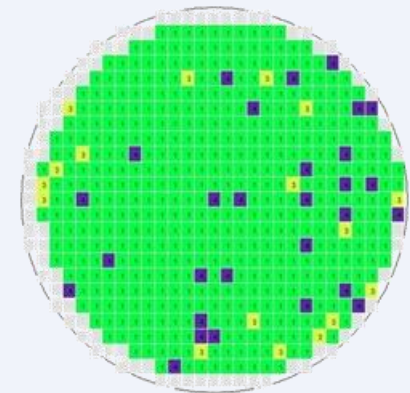
- Self-IP/Customized design & process platforms for SiC product
- Covering 650V~2000V rating
- MOSFET cell pitch size from 6.2um to 3.9um
- Latest  $R_{on,sp} < 3m\Omega.cm^2$
- AEC-Q101 certified at 2024. Nov



CP yield: 93.04%  
1200V/16mR

## ➤ Pure foundry service

- Customized process availability based on customer designs
- 80 tape-outs for 50+ customers
- Covering 650V~1700V rating
- Mass production since 2024 Q1



CP yield: 90.91%  
900V/11mR

# Turn key portfolio: SiC MOSFET



## Key Features

(G2 1200V 14mohm as example)

- $R_{sp} < 3\text{m}\Omega\cdot\text{cm}^2$
- Excellent FOM( $R_{dson}\cdot Q_g$ )
- Low  $R_{dson}$  shift from 25°C to 175°C
- Max  $V_{gs,op}$  -10V/22V
- $V_{th} \sim 2.8\text{V}@25^\circ\text{C}$
- Over 2us Short circuit capability
- Gate drive voltage 18V/15V
- Automotive grade

AscenPower SiC Mosfet

VDS (V)	Rdson (mΩ)	ID (A)	Gen	Bare Die	TO247-4L	TO263-7L
750	9	130	G2P	2026-Q1	2026-Q1	2026-Q2
	15	110	G2P	2026-Q1	2026-Q1	2026-Q2
	20	80	G2P	2026-Q1	2026-Q1	2026-Q2
	25	75	G2P	2025-Q3	2025-Q3	2025-Q4
	40	46	G2P	2026-Q1	2026-Q1	2026-Q2
	60	30	G2P	2026-Q1	2026-Q1	2026-Q2
1200	9	185	G3	2026-Q2	2026-Q2	
	11	165	G3	2026-Q1	2026-Q1	
	13	155	G2P	2025-Q2	2025-Q2	
	25	75	G2P	2026-Q1	2026-Q1	2026-Q2
	30	65	G2P	2026-Q1	2026-Q1	2026-Q2
	40	50	G2P	2026-Q1	2026-Q1	2026-Q2
	60	40	G2P	2026-Q1	2026-Q1	2026-Q2
	70	35	G2P	2026-Q1	2026-Q1	2026-Q2
	14	111	G2E	●	●	
	16	113	G1	●	●	
	30	59	G2	●	●	●
	32	62	G2	●	●	●
	60	34	G2	●	●	●
	120	20	G2	●	●	●
> 2000	25	92	G2P	2026-Q2		

Note:  $R_{dson}$  (Typ) @  $V_{gs}=18\text{V}$   $T_c=25^\circ\text{C}$ ,  $I_D@T_c=25^\circ\text{C}$

# Turn key portfolio: SiC SBD



AscenPower SiC SBD									
VDS (V)	IF (A)	VF (V)	Gen	Bare Die	TO247-2L	TO247-3L	TO-220	TO252	TO263-2L
650	10	1.3	2	2025-Q3			2025-Q3	2025-Q3	
	20	1.45	1	●	●	2025-Q2			
1200	30	1.42	1	●	●				
	100	1.45	1	●	2025-Q1				
	30	1.4	2	2025-Q3	2025-Q3				2025-Q3

Note: VF@IF (Typ) Tc=25°C

## Key Features

- Ultra low VF < 1.42@1200V
- High IFSM (forward surge Current) capability
- No reverse recovery current
- Low forward voltage at high temperature
- High switching performance

## Key Benefits

- Higher reliability thanks to a low leakage current
- Reduction of system complexity and cost
- Efficiency improvement
- Enabling higher frequency
- Improved efficiency over all load conditions



**AscenPower • Empower**